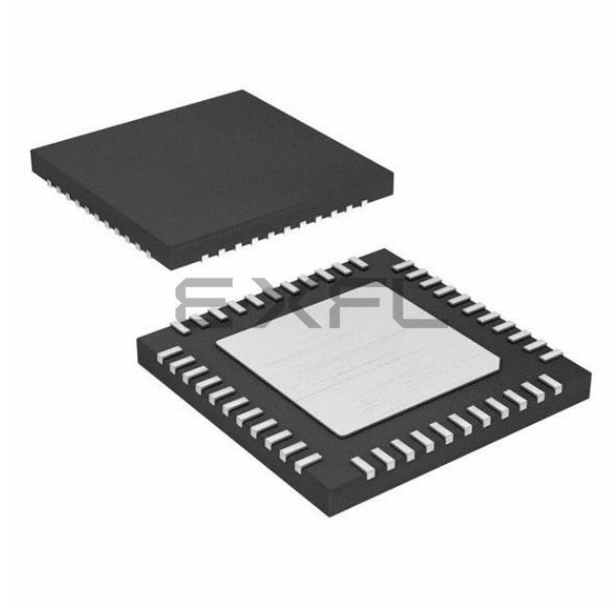

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I²C, IrDA, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	34
Program Memory Size	64KB (32K x 16)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 12x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	0°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	44-VFQFN Exposed Pad
Supplier Device Package	44-VQFN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atxmega64a4u-mnr

10. System Clock and Clock options

10.1 Features

- Fast start-up time
- Safe run-time clock switching
- Internal oscillators:
  - 32MHz run-time calibrated and tuneable oscillator
  - 2MHz run-time calibrated oscillator
  - 32.768kHz calibrated oscillator
  - 32kHz ultra low power (ULP) oscillator with 1kHz output
- External clock options
  - 0.4MHz - 16MHz crystal oscillator
  - 32.768kHz crystal oscillator
  - External clock
- PLL with 20MHz - 128MHz output frequency
  - Internal and external clock options and 1x to 31x multiplication
  - Lock detector
- Clock prescalers with 1x to 2048x division
- Fast peripheral clocks running at two and four times the CPU clock
- Automatic run-time calibration of internal oscillators
- External oscillator and PLL lock failure detection with optional non-maskable interrupt

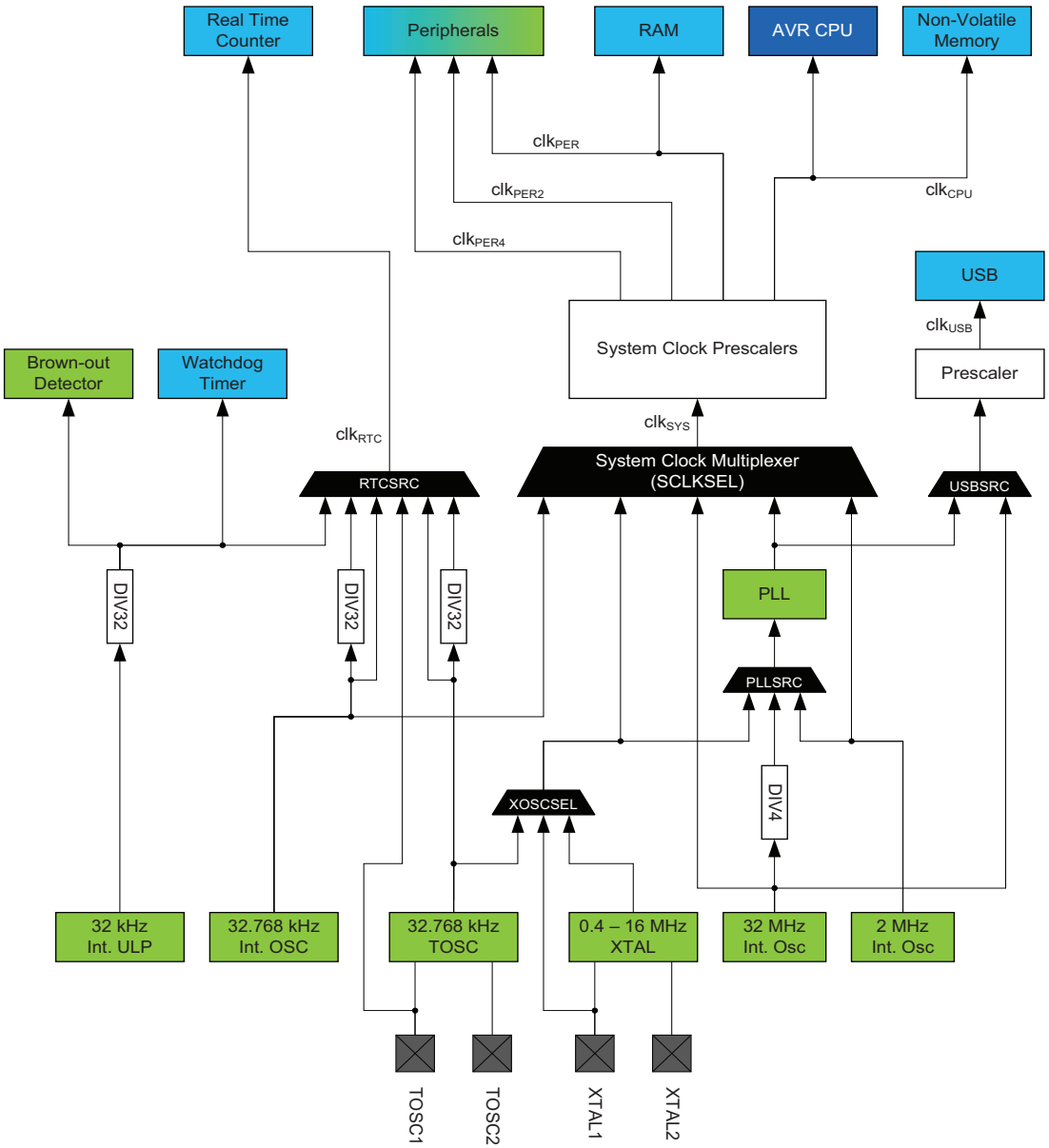
10.2 Overview

Atmel AVR XMEGA A4U devices have a flexible clock system supporting a large number of clock sources. It incorporates both accurate internal oscillators and external crystal oscillator and resonator support. A high-frequency phase locked loop (PLL) and clock prescalers can be used to generate a wide range of clock frequencies. A calibration feature (DFLL) is available, and can be used for automatic run-time calibration of the internal oscillators to remove frequency drift over voltage and temperature. An oscillator failure monitor can be enabled to issue a non-maskable interrupt and switch to the internal oscillator if the external oscillator or PLL fails.

When a reset occurs, all clock sources except the 32kHz ultra low power oscillator are disabled. After reset, the device will always start up running from the 2MHz internal oscillator. During normal operation, the system clock source and prescalers can be changed from software at any time.

Figure 10-1 on page 22 presents the principal clock system in the XMEGA A4U family of devices. Not all of the clocks need to be active at a given time. The clocks for the CPU and peripherals can be stopped using sleep modes and power reduction registers, as described in “Power Management and Sleep Modes” on page 24.

Figure 10-1. The clock system, clock sources and clock distribution.



10.3 Clock Sources

The clock sources are divided in two main groups: internal oscillators and external clock sources. Most of the clock sources can be directly enabled and disabled from software, while others are automatically enabled or disabled, depending on peripheral settings. After reset, the device starts up running from the 2MHz internal oscillator. The other clock sources, DFLLs and PLL, are turned off by default.

The internal oscillators do not require any external components to run. For details on characteristics and accuracy of the internal oscillators, refer to the device datasheet.

10.3.1 32kHz Ultra Low Power Internal Oscillator

This oscillator provides an approximate 32kHz clock. The 32kHz ultra low power (ULP) internal oscillator is a very low power clock source, and it is not designed for high accuracy. The oscillator employs a built-in prescaler that provides

12.4.2 Brownout Detection

The on-chip brownout detection (BOD) circuit monitors the V_{CC} level during operation by comparing it to a fixed, programmable level that is selected by the BODLEVEL fuses. If disabled, BOD is forced on at the lowest level during chip erase and when the PDI is enabled.

12.4.3 External Reset

The external reset circuit is connected to the external $\overline{\text{RESET}}$ pin. The external reset will trigger when the $\overline{\text{RESET}}$ pin is driven below the $\overline{\text{RESET}}$ pin threshold voltage, V_{RST}, for longer than the minimum pulse period, t_{EXT}. The reset will be held as long as the pin is kept low. The $\overline{\text{RESET}}$ pin includes an internal pull-up resistor.

12.4.4 Watchdog Reset

The watchdog timer (WDT) is a system function for monitoring correct program operation. If the WDT is not reset from the software within a programmable timeout period, a watchdog reset will be given. The watchdog reset is active for one to two clock cycles of the 2MHz internal oscillator. For more details see “WDT – Watchdog Timer” on page 28.

12.4.5 Software Reset

The software reset makes it possible to issue a system reset from software by writing to the software reset bit in the reset control register.The reset will be issued within two CPU clock cycles after writing the bit. It is not possible to execute any instruction from when a software reset is requested until it is issued.

12.4.6 Program and Debug Interface Reset

The program and debug interface reset contains a separate reset source that is used to reset the device during external programming and debugging. This reset source is accessible only from external debuggers and programmers.

Mnemonics	Operands	Description	Operation	Flags	#Clocks
ELPM	Rd, Z+	Extended Load Program Memory and Post-Increment	Rd ← (RAMPZ:Z), Z ← Z + 1	None	3
SPM		Store Program Memory	(RAMPZ:Z) ← R1:R0	None	-
SPM	Z+	Store Program Memory and Post-Increment by 2	(RAMPZ:Z) ← R1:R0, Z ← Z + 2	None	-
IN	Rd, A	In From I/O Location	Rd ← I/O(A)	None	1
OUT	A, Rr	Out To I/O Location	I/O(A) ← Rr	None	1
PUSH	Rr	Push Register on Stack	STACK ← Rr	None	1 (1)
POP	Rd	Pop Register from Stack	Rd ← STACK	None	2 (1)
XCH	Z, Rd	Exchange RAM location	Temp ← Rd, Rd ← (Z), (Z) ← Temp	None	2
LAS	Z, Rd	Load and Set RAM location	Temp ← Rd, Rd ← (Z), (Z) ← Temp v (Z)	None	2
LAC	Z, Rd	Load and Clear RAM location	Temp ← Rd, Rd ← (Z), (Z) ← ($FFh – Rd) • (Z)	None	2
LAT	Z, Rd	Load and Toggle RAM location	Temp ← Rd, Rd ← (Z), (Z) ← Temp ⊕ (Z)	None	2
Bit and bit-test instructions					
LSL	Rd	Logical Shift Left	Rd(n+1) ← Rd(n), Rd(0) ← 0, C ← Rd(7)	Z,C,N,V,H	1
LSR	Rd	Logical Shift Right	Rd(n) ← Rd(n+1), Rd(7) ← 0, C ← Rd(0)	Z,C,N,V	1
ROL	Rd	Rotate Left Through Carry	Rd(0) ← C, Rd(n+1) ← Rd(n), C ← Rd(7)	Z,C,N,V,H	1
ROR	Rd	Rotate Right Through Carry	Rd(7) ← C, Rd(n) ← Rd(n+1), C ← Rd(0)	Z,C,N,V	1
ASR	Rd	Arithmetic Shift Right	Rd(n) ← Rd(n+1), n=0..6	Z,C,N,V	1
SWAP	Rd	Swap Nibbles	Rd(3..0) ↔ Rd(7..4)	None	1
BSET	s	Flag Set	SREG(s) ← 1	SREG(s)	1
BCLR	s	Flag Clear	SREG(s) ← 0	SREG(s)	1
SBI	A, b	Set Bit in I/O Register	I/O(A, b) ← 1	None	1
CBI	A, b	Clear Bit in I/O Register	I/O(A, b) ← 0	None	1
BST	Rr, b	Bit Store from Register to T	T ← Rr(b)	T	1
BLD	Rd, b	Bit load from T to Register	Rd(b) ← T	None	1
SEC		Set Carry	C ← 1	C	1
CLC		Clear Carry	C ← 0	C	1
SEN		Set Negative Flag	N ← 1	N	1
CLN		Clear Negative Flag	N ← 0	N	1
SEZ		Set Zero Flag	Z ← 1	Z	1

Table 36-32. Two-wire interface characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{IH}	Input high voltage		$0.7*V_{CC}$		$V_{CC}+0.5$	V
V_{IL}	Input low voltage		0.5		$0.3*V_{CC}$	V
V_{hys}	Hysteresis of Schmitt trigger inputs		$0.05*V_{CC}$ (1)			V
V_{OL}	Output low voltage	3mA, sink current	0		0.4	V
t_r	Rise time for both SDA and SCL		$20+0.1C_b$ (1)(2)		300	ns
t_{of}	Output fall time from V_{IHmin} to V_{ILmax}	$10pF < C_b < 400pF$ (2)	$20+0.1C_b$ (1)(2)		250	ns
t_{SP}	Spikes suppressed by input filter		0		50	ns
I_I	Input current for each I/O Pin	$0.1V_{CC} < V_I < 0.9V_{CC}$	-10		10	µA
C_I	Capacitance for each I/O Pin				10	pF
f_{SCL}	SCL clock frequency	f_{PER} (3)>max($10f_{SCL}$, 250kHz)	0		400	kHz
R_P	Value of pull-up resistor	$f_{SCL} \leq 100kHz$	$\frac{V_{CC}-0.4V}{3mA}$		$\frac{100ns}{C_b}$	Ω
		$f_{SCL} > 100kHz$			$\frac{300ns}{C_b}$	
$t_{HD;STA}$	Hold time (repeated) START condition	$f_{SCL} \leq 100kHz$	4.0			µs
		$f_{SCL} > 100kHz$	0.6			
t_{LOW}	Low period of SCL clock	$f_{SCL} \leq 100kHz$	4.7			µs
		$f_{SCL} > 100kHz$	1.3			
t_{HIGH}	High period of SCL clock	$f_{SCL} \leq 100kHz$	4.0			µs
		$f_{SCL} > 100kHz$	0.6			
$t_{SU;STA}$	Set-up time for a repeated START condition	$f_{SCL} \leq 100kHz$	4.7			µs
		$f_{SCL} > 100kHz$	0.6			
$t_{HD;DAT}$	Data hold time	$f_{SCL} \leq 100kHz$	0		3.45	µs
		$f_{SCL} > 100kHz$	0		0.9	
$t_{SU;DAT}$	Data setup time	$f_{SCL} \leq 100kHz$	250			ns
		$f_{SCL} > 100kHz$	100			
$t_{SU;STO}$	Setup time for STOP condition	$f_{SCL} \leq 100kHz$	4.0			µs
		$f_{SCL} > 100kHz$	0.6			
t_{BUF}	Bus free time between a STOP and START condition	$f_{SCL} \leq 100kHz$	4.7			µs
		$f_{SCL} > 100kHz$	1.3			

Notes:
1. Required only for $f_{SCL} > 100kHz$.
2. C_b = Capacitance of one bus line in pF.
3. f_{PER} = Peripheral clock frequency.

Table 36-42. Accuracy characteristics.

Symbol	Parameter	Condition [2]		Min.	Typ.	Max.	Units
RES	Resolution	Programmable to 8 or 12 bit		8	12	12	Bits
INL[1]	Integral non-linearity	500ksps	V_{CC}-1.0V < V_{REF}< V_{CC}-0.6V		±1.2	±2.0	lsb
			All V_{REF}		±1.5	±3.0	
		2000ksps	V_{CC}-1.0V < V_{REF}< V_{CC}-0.6V		±1.0	±2.0	
			All V_{REF}		±1.5	±3.0	
DNL[1]	Differential non-linearity	guaranteed monotonic			<±0.8	<±1.0	lsb
	Offset error				-1.0		mV
		Temperature drift			<0.01		mV/K
		Operating voltage drift			<0.6		mV/V
	Gain error	Differential mode	External reference		-1.0		mV
			AV_{CC}/1.6		10		
			AV_{CC}/2.0		8.0		
			Bandgap		±5.0		
		Temperature drift			<0.02		mV/K
		Operating voltage drift			<0.5		mV/V
	Noise	Differential mode, shorted input 2msps, V_{CC} = 3.6V, Clk_{PER} = 16MHz			0.4		mV rms

Notes:
1. Maximum numbers are based on characterisation and not tested in production, and valid for 5% to 95% input voltage range.
2. Unless otherwise noted all linearity, offset and gain error numbers are valid under the condition that external V_{REF} is used.

Table 36-43. Gain stage characteristics.

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
R_{in}	Input resistance	Switched in normal mode			4.0		kΩ
C_{sample}	Input capacitance	Switched in normal mode			4.4		pF
	Signal range	Gain stage output		0		V_{CC}- 0.6	V
	Propagation delay	ADC conversion rate			1.0		Clk_{ADC} cycles
	Sample rate	Same as ADC		100		1000	kHz
INL [1]	Integral non-linearity	500ksps	All gain settings		±1.5	±4.0	lsb
	Gain error	1x gain, normal mode			-0.8		%
		8x gain, normal mode			-2.5		
		64x gain, normal mode			-3.5		

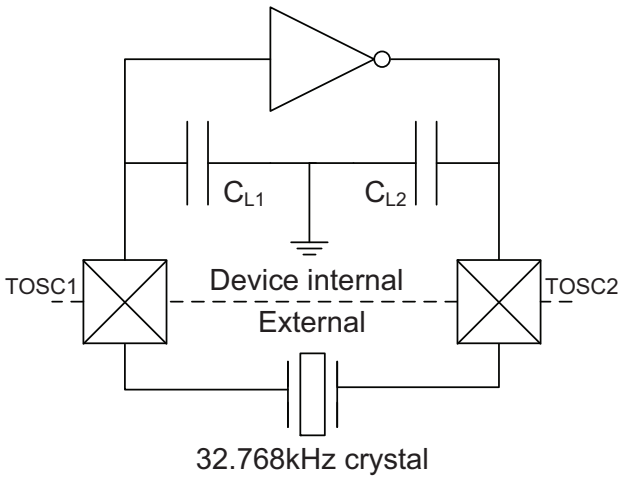
36.2.14.8 External 32.768kHz crystal oscillator and TOSC characteristics

Table 36-62. External 32.768kHz crystal oscillator and TOSC characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
ESR/R1	Recommended crystal equivalent series resistance (ESR)	Crystal load capacitance 6.5pF			60	kΩ
		Crystal load capacitance 9.0pF			35	
C_{TOSC1}	Parasitic capacitance TOSC1 pin			5.4		pF
		Alternate TOSC location		4.0		
C_{TOSC2}	Parasitic capacitance TOSC2 pin			7.1		pF
		Alternate TOSC location		4.0		
	Recommended safety factor	capacitance load matched to crystal specification	3.0			

Note: 1. See Figure 36-11 for definition.

Figure 36-11.TOSC input capacitance.



The parasitic capacitance between the TOSC pins is C_{L1} + C_{L2} in series as seen from the crystal when oscillating without external capacitors.

36.2.15 SPI Characteristics

Figure 36-12. SPI timing requirements in master mode.

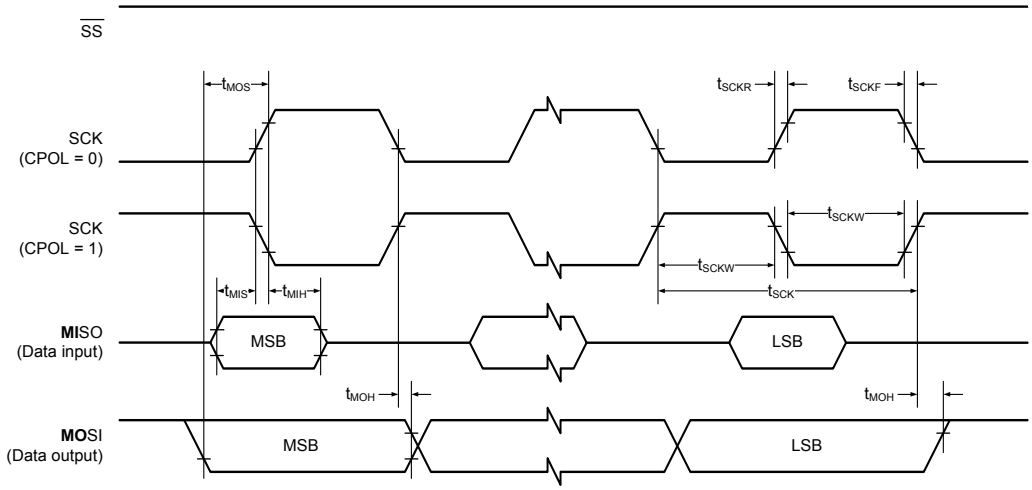


Figure 36-13. SPI timing requirements in slave mode.

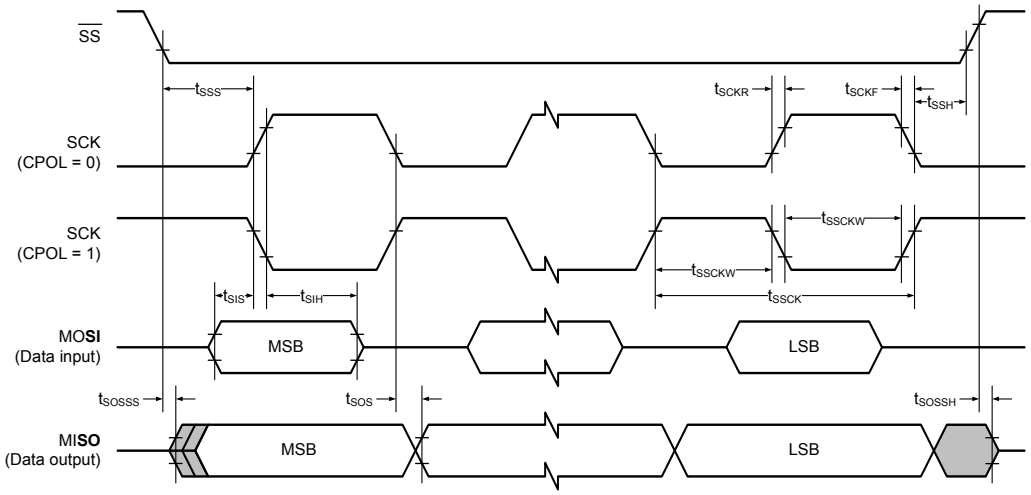


Figure 37-29. I/O pin output voltage vs. sink current.

V_{CC} = 3.0V.

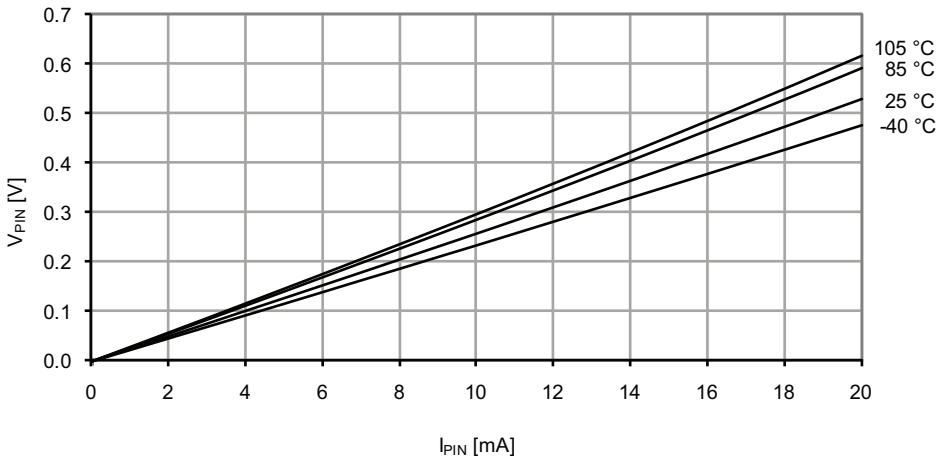


Figure 37-30. I/O pin output voltage vs. sink current.

V_{CC} = 3.3V.

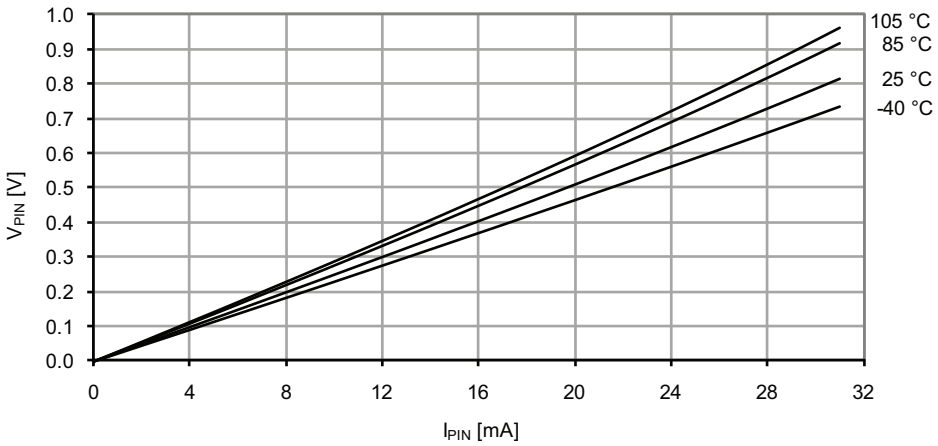
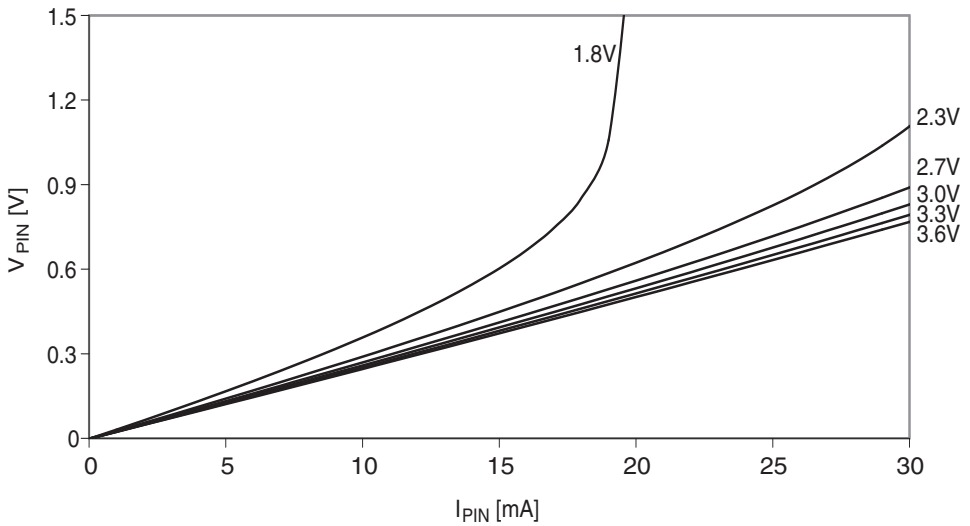


Figure 37-31. I/O pin output voltage vs. sink current.



37.1.3 ADC Characteristics

Figure 37-36. INL error vs. external V_{REF}.

$T = 25°C$, $V_{CC} = 3.6V$, external reference.

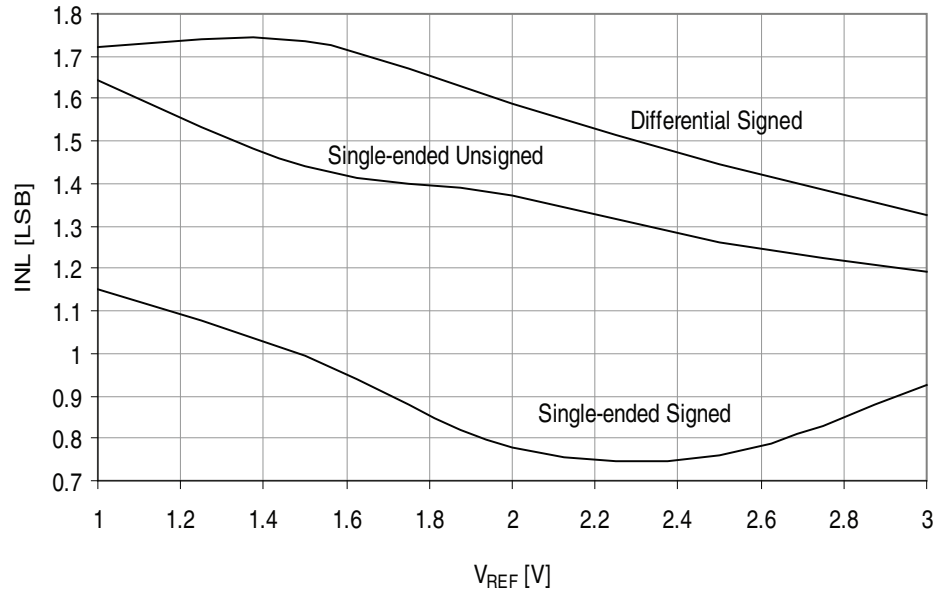


Figure 37-37. INL error vs. sample rate.

$T = 25°C$, $V_{CC} = 3.6V$, $V_{REF} = 3.0V$ external.

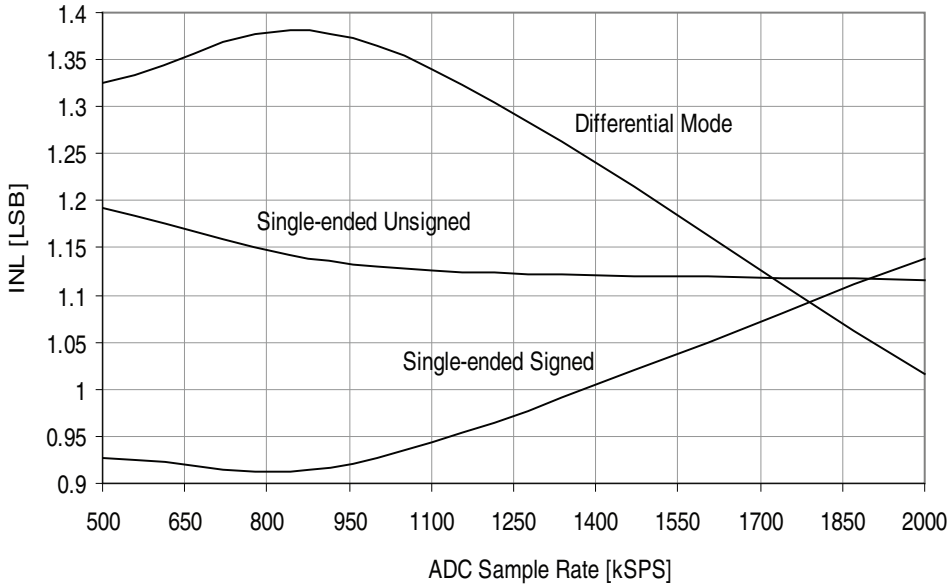


Figure 37-42. Gain error vs. V_{REF}.

T = 25°C, V_{CC} = 3.6V, ADC sampling speed = 500ksps.

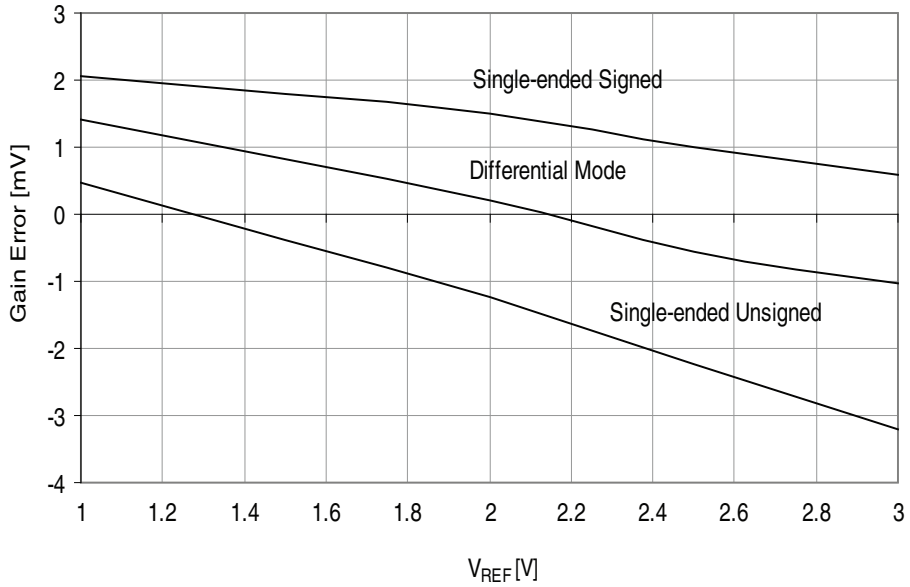


Figure 37-43. Gain error vs. V_{CC}.

T = 25°C, V_{REF} = external 1.0V, ADC sampling speed = 500ksps.

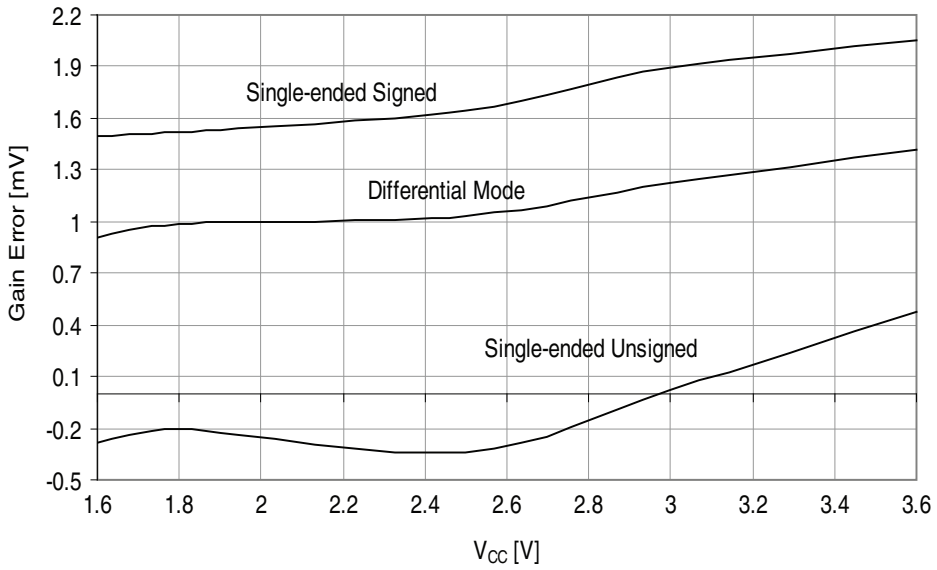


Figure 37-93.Idle mode supply current vs. frequency.

f_{SYS} = 1 - 32MHz external clock, T = 25°C.

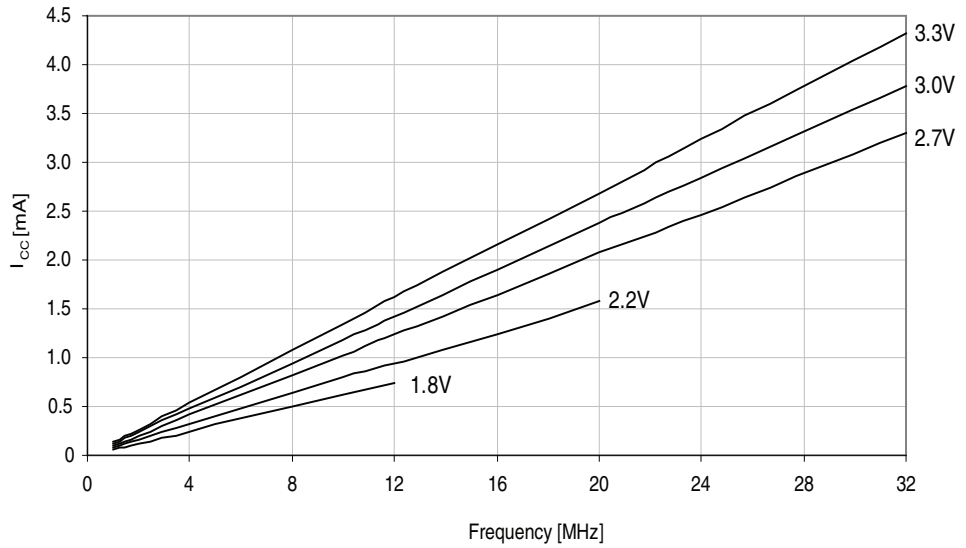


Figure 37-94. Idle mode supply current vs. V_{CC}.

f_{SYS} = 32.768kHz internal oscillator.

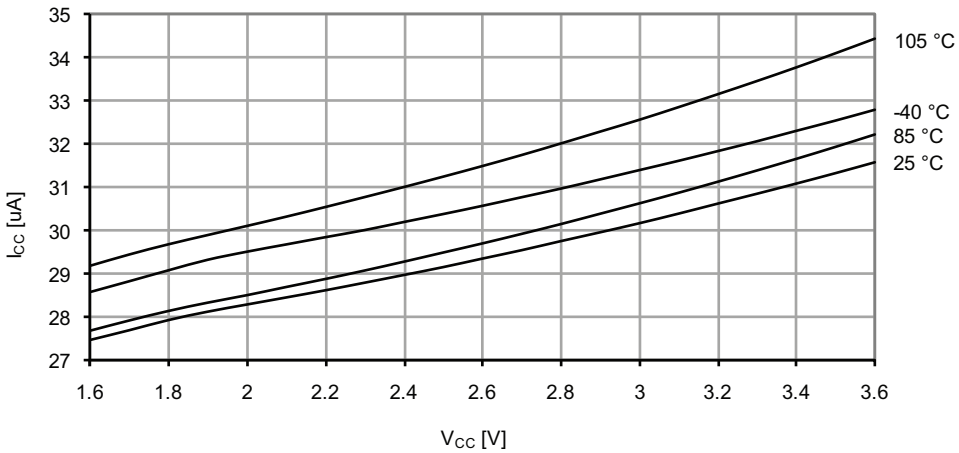
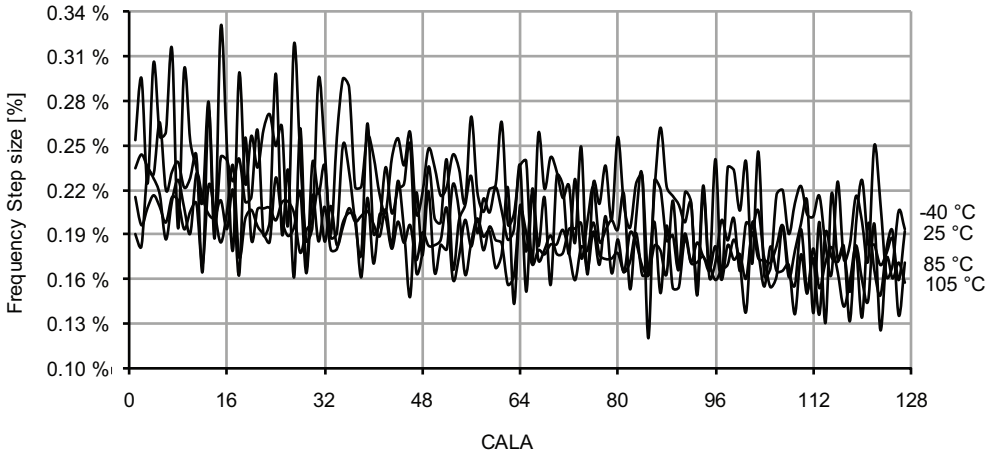


Figure 37-166. 48MHz internal oscillator CALA calibration step size.

V_{CC} = 3.0V.



37.2.11 Two-Wire Interface characteristics

Figure 37-167. SDA hold time vs. supply voltage.

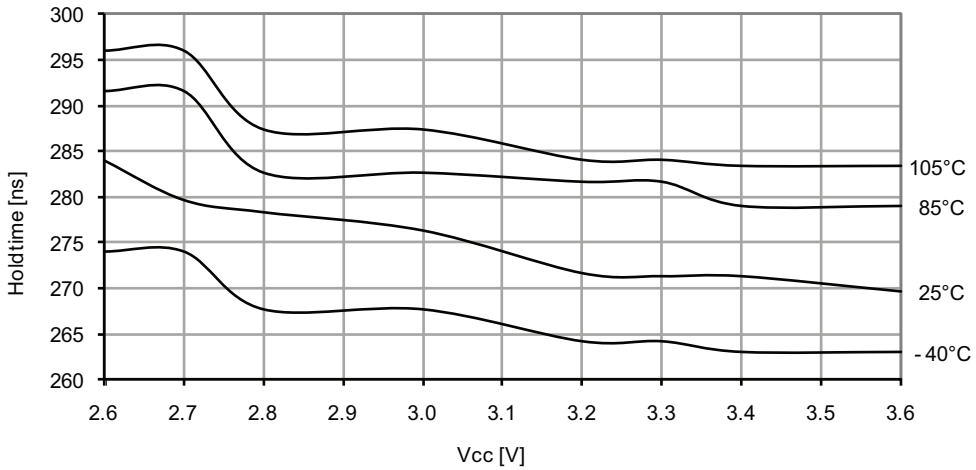


Figure 37-197. I/O pin output voltage vs. sink current.

V_{CC} = 3.0V.

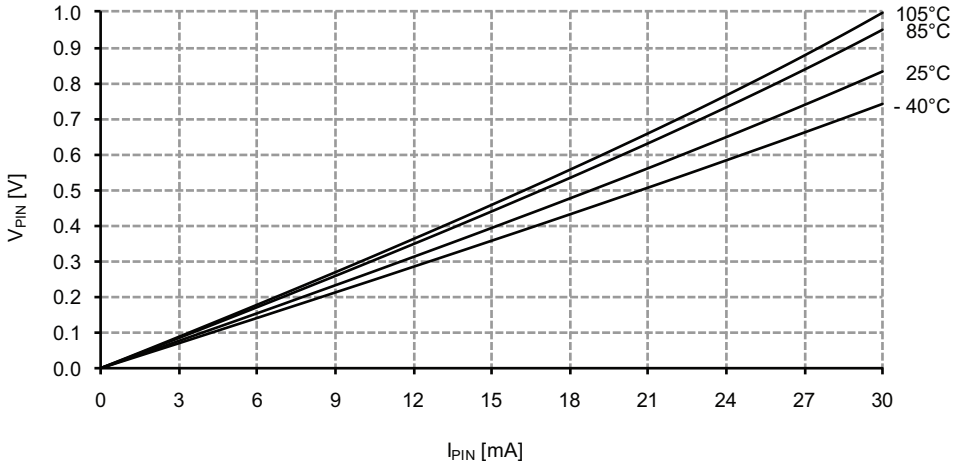


Figure 37-198. I/O pin output voltage vs. sink current.

V_{CC} = 3.3V.

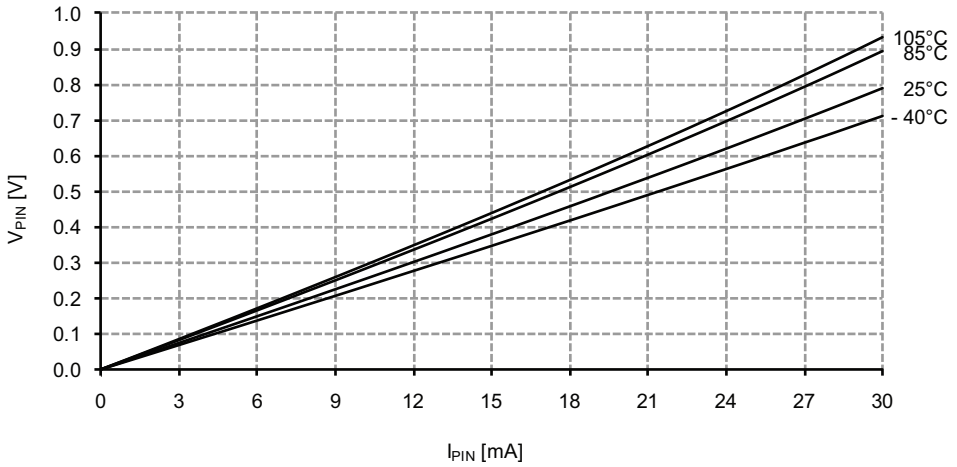


Figure 37-213. Gain error vs. temperature.

V_{CC} = 2.7V, V_{REF} = external 1.0V.

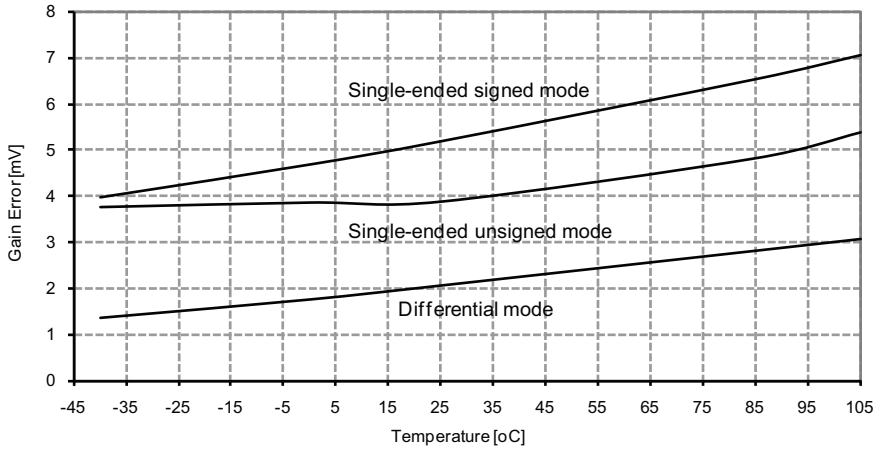


Figure 37-214. Offset error vs. V_{CC}.

T = 25°C, V_{REF} = external 1.0V, ADC sampling speed = 500ksps.

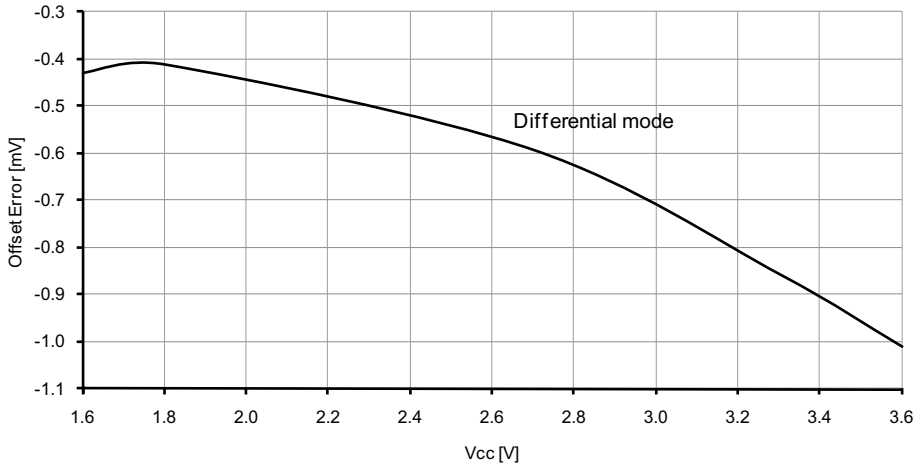


Figure 37-225. Analog comparator current source vs. calibration value.

V_{CC} = 3.0V.

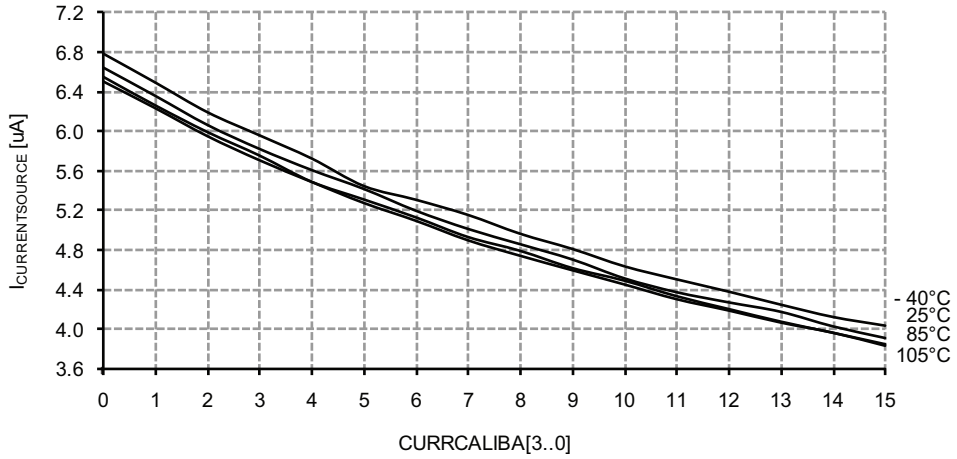


Figure 37-226. Voltage scaler INL vs. SCALEFAC.

T = 25°C, V_{CC} = 3.0V.

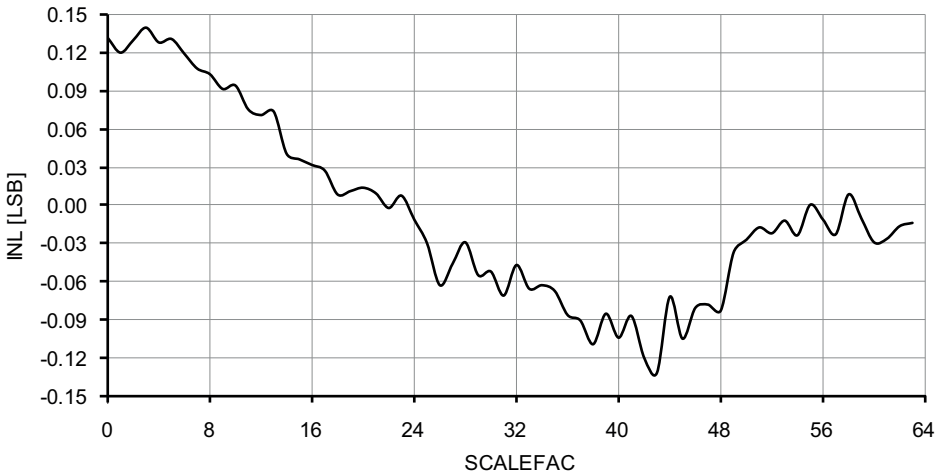
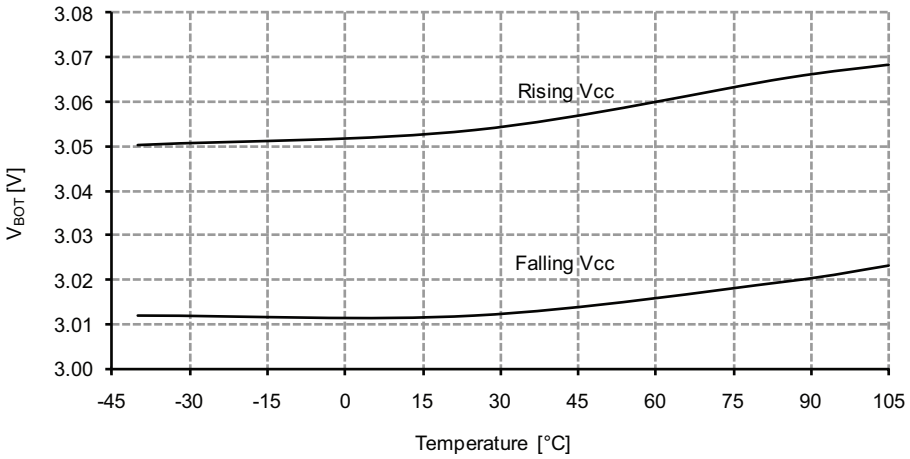


Figure 37-229. BOD thresholds vs. temperature.

BOD level = 3.0V.



37.3.8 External Reset Characteristics

Figure 37-230. Minimum Reset pin pulse width vs. V_{CC}.

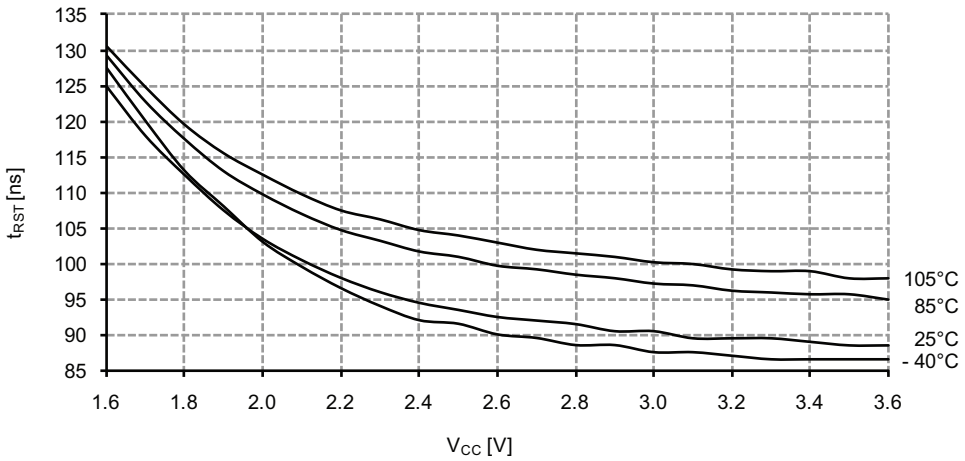
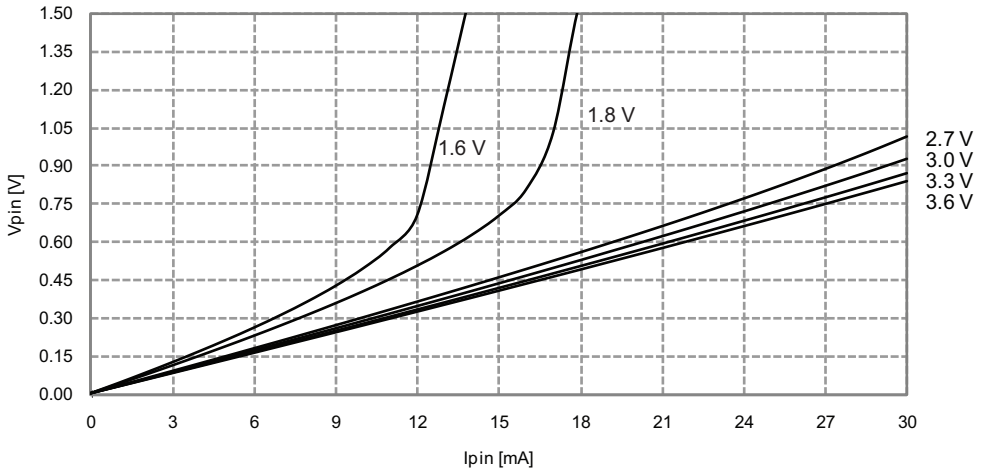


Figure 37-283. I/O pin output voltage vs. sink current



37.4.2.3 Thresholds and Hysteresis

Figure 37-284. I/O pin input threshold voltage vs. V_{CC}.

T = 25°C

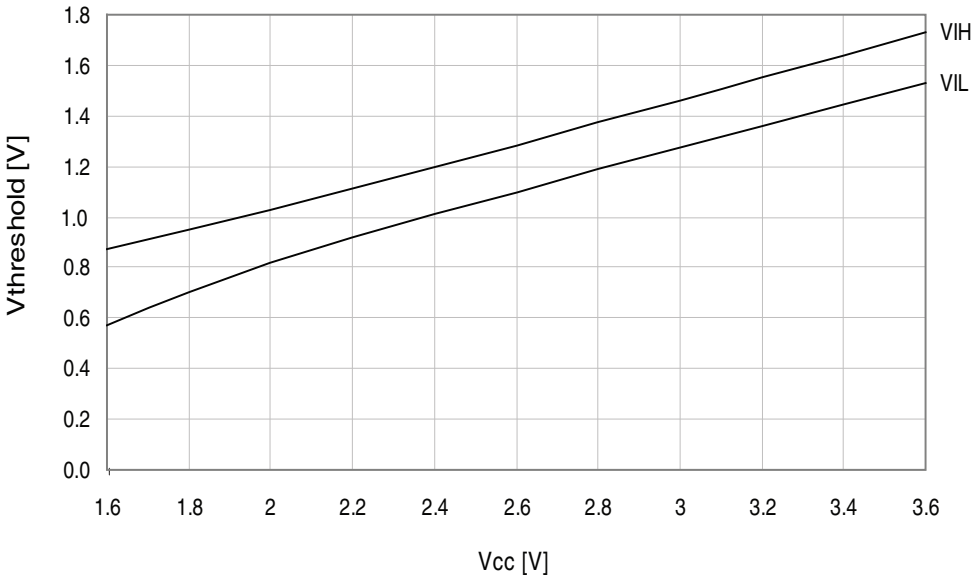


Figure 37-315. Reset pin pull-up resistor current vs. reset pin voltage

V_{CC} = 1.8V

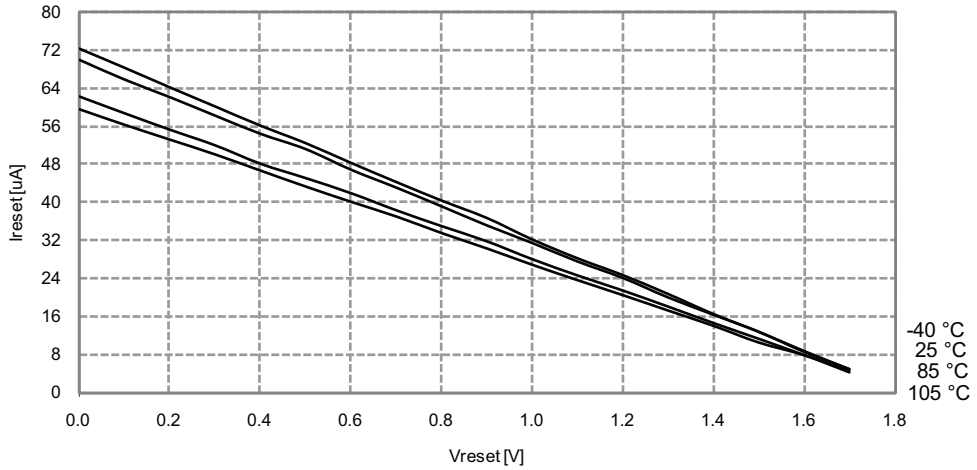
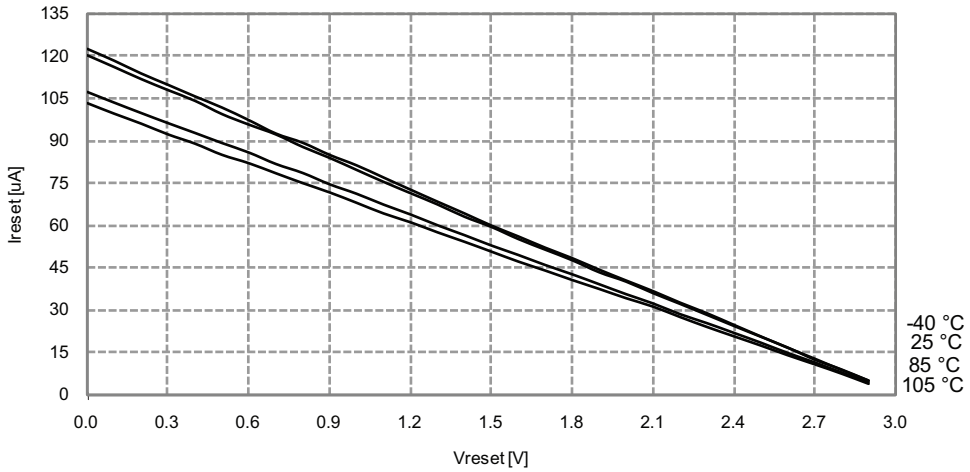


Figure 37-316. Reset pin pull-up resistor current vs. reset pin voltage

V_{CC} = 3.0V



37.4.10.5 32MHz internal oscillator calibrated to 48MHz

Figure 37-331. 48MHz internal oscillator frequency vs. temperature

DFLL disabled

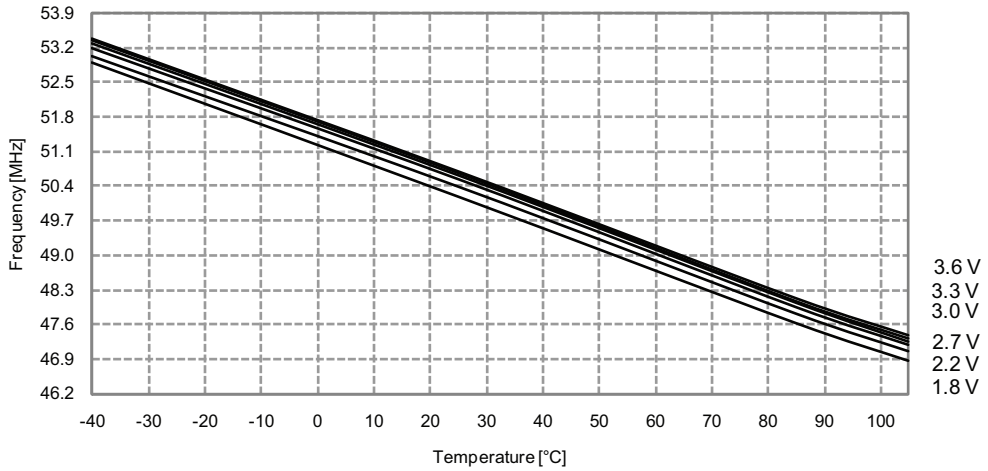


Figure 37-332. 48MHz internal oscillator frequency vs. temperature

DFLL enabled, from the 32.768kHz internal oscillator